

#2

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 209262US2		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hiroyuki MIYAKE, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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	AC						
	AD						
	AE						
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	AG						
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	AI						
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	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	11-17992	01/22/99	Japan (with English abstract)			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner <i>W.D. Bao</i>					Date Considered <i>1/14/04</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

11038 U.S. PTO
09/880016

06/14/01



#4

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY DOCKET NO. 209262US2		SERIAL NO. 09/880,016	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hiroyuki MIYAKE, et al.			
				FILING DATE June 14, 2001		GROUP 2681	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>not</i>	AO	11-191865	07/13/99	JAPAN (with English Abstract)			X
<i>not</i>	AP	WO 97/26744	07/24/97	WIPO			
<i>not</i>	AQ	08-294030	11/05/96	JAPAN (with English Abstract)			X
<i>not</i>	AR	1 081 944	03/07/2001	EUROPE			
<i>not</i>	AS	1 148 716	10/24/2001	EUROPE			
	AT						
	AU						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AV						
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Examiner <i>W. L. P. Davis</i>					Date Considered <i>1/14/04</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

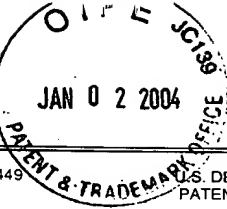
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JAN 02 2004

SHEET 1 OF 1

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

209262US2

SERIAL NO.

09/880,016

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hiroyuki MIYAKE, et al.

FILING DATE

June 14, 2001

GROUP

2681

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>mod</i>	AO	2000-324541	11/24/2000	JAPAN (with English Abstract)		X
<i>mod</i>	AP	10-313452	11/24/1998	JAPAN (with English Abstract)		X
<i>mod</i>	AQ	2000-92360	03/31/2000	JAPAN (with English Abstract)		X
<i>mod</i>	AR	1-286592	11/17/1989	JAPAN (with English Abstract)		X
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

mgr. Kao

Date Considered

1/14/04

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